

Receipt date: 10/17/2005

10528894 - GAU: 1631

FORM - 1449

SHEET 1 OF 3

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.

2001B101B

SERIAL NO.

10/528,894

APPLICANT

Robert L. LONG et al.

FILING DATE

05/08/2003

GROUP

Not Yet Assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/RSN/	AA	3,725,378	04/03/1973	Chamberlin			
	AB	3,779,712	12/18/1973	Calvert et al.			
	AC	4,175,169	11/20/1979	Beals et al.			
	AD	4,182,810	01/08/1980	Willcox			
	AE	4,243,619	01/06/1981	Fraser et al.			
	AF	4,469,853	09/04/1984	Mori			
	AG	4,543,399	09/24/1985	Jenkins, III et al.			
	AH	4,588,790	05/13/1986	Jenkins, III et al.			
	AI	4,620,049	10/28/1986	Schmidt et al.			
	AJ	4,621,952	11/11/1986	Aronson			
	AK	4,888,704	12/19/1989	Topliss et al.			
	AL	5,096,634	03/17/1992	Tsadares et al.			
	AM	5,121,337	06/09/1992	Brown			
	AN	5,151,474	09/29/1992	Lange et al.			
	AO	5,202,395	04/13/1993	Chambon			
	AP	5,270,274	12/14/1993	Hashiguchi et al.			
	AQ	5,274,056	12/28/1993	McDaniel et al.			
	AR	5,352,749	10/04/1994	DeChellis et al.			
	AS	5,405,922	04/11/1995	DeChellis et al.			
	AT	5,436,304	07/25/1995	Griffin et al.			
	AU	5,462,999	10/31/1995	Griffin et al.			
	AV	5,589,555	12/31/1996	Zboril et al.			
	AW	5,638,172	06/10/1997	Alsmeyer et al.			
	AX	5,675,253	10/07/1997	Smith et al.			
	AY	5,678,751	10/21/1997	Buchanan et al.			
	AZ	5,682,309	10/28/1997	Bartusiak et al.			
	AAA	5,696,213	12/09/1997	Schiffino et al.			

EXAMINER

/Russell S. Negin/

DATE CONSIDERED

02/19/2009

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next comment to applicant

Receipt date: 10/17/2005

10528894 - GAU: 1631

FORM - 1449

SHEET 2 OF 3

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.

SERIAL NO.

2001B101B

10/528,894

APPLICANT

Robert L. LONG et al.

FILING DATE

GROUP

05/08/2003

Not Yet Assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/RSN/	AA	5,892,228	04/06/1999	Cooper et al.			
	AB	5,999,255	12/07/1999	Dupee et al.			
	AC	6,072,576	06/06/2000	McDonald et al.			
	AD	6,144,897	11/07/2000	Selliers			
	AE	6,204,664	03/20/2001	Sardashti et al.			
	AF	6,218,484	04/17/2001	Brown et al.			
	AG	6,405,579	06/18/2002	Tjahjadi et al.			
	AH	6,479,597	11/12/2002	Long et al.			
	AI	6,673,878	01/06/2004	Donck			
	AJ	2004/0233425	11/25/2004	Long et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBL. DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AK	EP 238 796	30.09.87	Europe				
	AI	EP 406 805	13.12.95	Europe				
/RSN/	AM	EP 561 78 B1	23.04.97	Europe				
	AN	JP 02038841	1990.02.08	Japan (w/Abstract)				
/RSN/	AO	WO 94/21962	29.09.94	PCT				
	AP	WO 96/41822	27.12.96	PCT				
	AQ	WO 98/08066	26.02.98	PCT				
	AR	WO 99/01750	14.01.99	PCT				
	AS	WO 01/09201	08.02.01	PCT				
	AT	WO 01/09203	08/02/01	PCT				

OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages of Publication, Etc.)

/RSN/	AU	K.R. Beebe et al., "An Introduction to Multivariate Calibration and Analysis," Analytical Chemistry, Vol. 59, No. 17, pp.1007A-1017A, Sept. 1, 1987.
/RSN/	AV	J. M. Tedesco et al., "Calibration of dispersive Raman Process Analyzers," The Society Of Photo-Optical Instrumentation Engineers, Vol. 3537, pp. 200-212, 1999.
/RSN/	AW	G.A. Bakken et al., "Examination of Criteria for Local Model Principal Component Regression," Society for Applied Spectroscopy, Vol. 51, No. 12, pp. 1814-1822, 1997.

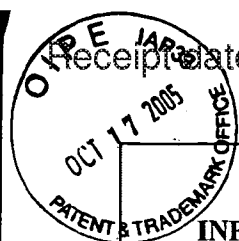
EXAMINER

/Russell S. Negin/

DATE CONSIDERED

02/19/2009

* EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line though citation if not in conformance and not considered. Include copy of this form with next comment to applicant



Receipt Date: 10/17/2005

10528894 - GAU: 1631

FORM - 1449

SHEET 3 OF 3

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.

2001B101B

SERIAL NO.

10/528,894

APPLICANT

Robert L. LONG et al.

FILING DATE

05/08/2003

GROUP

Not Yet Assigned

OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages of Publication, Etc.)

/RSN/	AA	P. Erlich et al., " <u>Fundamentals of the Free-Radical Polymerization of Ethylene</u> ," Advanced Polymer Science, Vol. 7, pp. 386-448, 1970.
	AB	M.L. Myrick et al., " <u>In Situ Fiber-Optic Raman Spectroscopy of Organic Chemistry in a Supercritical Water Reactor</u> ," Journal of Raman Spectroscopy, Vol. 25, pp. 59-65, 1994.
	AC	T. Naes et al., " <u>Locally Weighted Regression and Scatter Correction for Near-Infrared Reflectance Data</u> ," Analytical Chemistry, Vol. 62, pp. 664-673, 1990.
	AD	G.G. Ardell et al., " <u>Model Prediction for Reactor Control</u> ," Chemical Engineering Progress, American Institute of Chemical Engineers, Vol. 79, No. 6, pp. 77-83, June 1, 1983.
	AE	J.J. Zacca et al., " <u>Modelling of the Liquid Phase Polymerization of Olefins in Loop reactors</u> ," Chemical Engineering Science, Vol. 48, No. 22, pp. 3743-3765, 1993.
	AF	L.P. Russo et al., " <u>Moving-Horizon State Estimation Applied to an Industrial Polymereization Process</u> ," American Control Conf. Proc., San Diego, CA, 1999.
	AG	H. Martens et al., " <u>Multivariate Calibration</u> ," Wiley & Sons Ltd., pp. viii-ix, 1989.
	AH	<u>Multivariate Data Analysis for Windows - Version 3.0</u> , excerpted from Pirouette Software Manual, Exploratory Analysis: Principal Component Analysis, pp. 5-13 through 5-40, 1985-2000.
	AI	E.P.C. Lai et al., " <u>Noninvasive Spectroscopic Detection of Bulk Polymerization by Stimulated Raman Scattering</u> ," Applied Spectroscopy, Vol. 48, No. 8, 1994.
	AJ	S. Sekulic et al., " <u>Nonlinear Multivariate Calibration Methods in Analytical Chemistry</u> ," Analytical Chemistry, Vol 65, No. 19, pp. 835A-845A, Oct. 1, 1993.
	AK	E.D. Lipp et al., " <u>On-Line Monitoring Of Chlorosilane Streams By Raman Spectroscopy</u> ," Reprinted from Applied Spectroscopy, Vol 52, No. 1, January, 1998.
	AL	D.R. Battiste et al., " <u>On-Line Raman Analysis of Ethylene and Hexene in the Phillips 1-Hexene and Polyethylene Processes</u> ," Gulf Coast Conference presentation (Abstract)
	AM	M.J. Pelletier et al.; " <u>Optical fibers enable Raman instruments to analyze industrial process problems quickly and accurately</u> ," Raman Spectroscopy—Keeps Industry Under Control, Reprint: Photonics Spectra, 4 pgs., October, 1997.
	AN	V. Centner et al., " <u>Optimization in Locally Weighted Regression</u> ," Analytical Chemistry, Vol. 70, No. 19, pp. 4206-4211, Oct. 1, 1998.
	AO	<u>"Principal Components Analysis"</u> , excerpted from PLS_Toolbox, Version 2.0 Data Analysis Manual, Eigenvector Research, Inc., pp. 32-34, 1998.
	AP	L. Markwort et al., " <u>Raman Imaging of Heterogeneous Polymers: A Comparison of Global versus Point Illumination</u> ," Applied Spectroscopy, Vol. 49, No. 10, pp. 1411-1430, 1995.
	AO	I. Modric et al. "Raman- und Infrarotspektren isotaktischer Polyallyldithiolen*," Colloid & Polymer Sci., Vol. 254, pp. 342-347, 1976.
/RSN/	AR	M.G. Hansen et al., " <u>Real-Time Monitoring of Industrial Polymers</u> ," Raman Review; pp. 1-4, 3/98.
/RSN/	AS	S.E. Nave "Rugged Fiber Optic Probes and Sampling Systems for Remote Chemical Analysis Via the Raman Technique," ISA, Paper #96-042, pp. 453-467, 1996.
/RSN/	AT	M.J. Pelletier et al., " <u>Shining a Light on Wet Process Control</u> ," Semiconductor International, 4 pages, March, 1996.
/RSN/	AU	K.P.J. Williams et al., " <u>Use of Micro Raman Spectroscopy for the Quantitative Determination of Polyethylene Density Using Partial Least-Squares Calibration</u> ," Journal of Raman Spectroscopy, Vol. 26, pp. 427-433, 1995.

EXAMINER

/Russell S. Negin/

DATE CONSIDERED

02/19/2009

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line though citation if not in conformance and not considered. Include copy of this form with next comment to applicant